

Application/Control No.	No. Applicant(s)/Patent under Reexamination	
10/071,263	CAIA, JEAN-MICHEL	
Examiner	Art Unit	
PHUC H. TRAN	2616	

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Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
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SEARCH (INCLUDING SEAR)
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text search for interference	10/24/2007	PT
East update search	10/24/2007	P.T
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